MeasureReady[™] M91 FastHall[™] Measurement Controller





MeasureReady™ M91 FastHall™ Measurement Controller

A new approach to Hall measurement

The MeasureReady M91 is a revolutionary, all-in-one Hall analysis instrument that delivers significantly higher levels of precision, speed, and convenience to researchers involved in the study of electronic materials.

Featuring Lake Shore's patented* new FastHall measurement technique, the M91 fundamentally changes the way the Hall effect is measured by eliminating the need to switch the polarity of the applied magnetic field during the measurement. This breakthrough results in faster and more precise measurements, especially when using high field superconducting magnets or when measuring very low mobility materials.

*Protected by US patent numbers 9797965 and 10073151. Other patents pending.



Simpler and more convenient

- All-in-one instrument
- Automatically selects optimal excitation and measurement levels
- Automatically executes measurement steps
- Provides complete Hall analysis
- Easy to use, easy to integrate with existing lab systems



Makes better measurements, faster

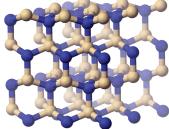
- No need to reverse the magnetic field with FastHall
- Up to 100× faster for low mobility materials
- Improves accuracy by minimizing thermal drift



Cost effective

- Build a new Hall system or upgrade an existing one
- Add state-of-the-art Hall measurement capability to any lab
- Use with any type of magnet





Ideal for measuring low mobility materials

MeasureReady M91 FastHall measurement controller automatically checks sample contact quality and graphically displays results.



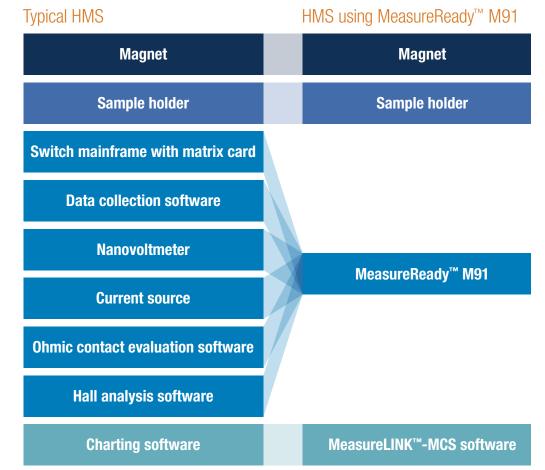
Executes a complete Hall measurement sequence:



A convenient, single instrument

Traditional Hall effect measurement systems (HMS) provide basic electrical measurement instrumentation combined with a switching unit to measure sample resistivity and Hall voltages, but must rely on separate PC-based software to perform pre- and post-measurement calculations in order to ultimately derive the physical parameters that researchers need to knowresistivity, carrier type, carrier concentration, mobility, and Hall coefficient.

The M91 FastHall measurement controller combines all of the necessary HMS functions into a single instrument, automating and optimizing the measurement process, and directly reporting the calculated parameters.



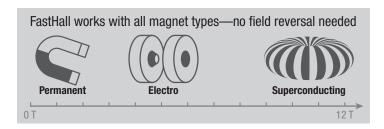
Adding HMS capabilities to any research platform has never been easier!

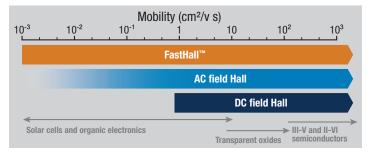
Better measurements in less time

Lake Shore's patented new FastHall technology eliminates the need to reverse the field, significantly reducing the time to make measurements without reducing measurement quality. In fact, a shorter measurement window lessens the opportunity for sample parameters to drift due to self-heating or ambient temperature change.

A unidirectional field also removes potential sources of measurement bias due field alignment errors, further improving the quality of the result.

With FastHall, any type of magnet can be used. For research platforms with high field superconducting magnets, the elimination of field reversal is especially beneficial.



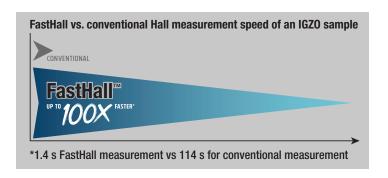


Ideal for low mobility materials

Traditional DC field Hall effect measurement is relatively straightforward and reliable for simpler materials with higher mobilities. Measurement difficulty increases and accuracy decreases as carrier mobilities decrease. This is often the case in promising new semiconductor materials such as photovoltaics, thermoelectrics, and organics.

AC field techniques using advanced lock-in amplifiers and longer measurement windows can extract smaller Hall voltage signals and are commonly used today to explore low mobility materials. Extended measurement intervals can also add error from thermal drift effects and results take longer to get—sometimes many hours.

The FastHall technique eliminates both of these issues — it precisiely measures even extremely low mobility materials in seconds.



The DC field Hall effect process requires taking voltage measurements with the magnetic field set in one direction, followed by reversal of the field polarity and repetition of the voltage measurements. The type of magnet used and the number of measurement samples needed for satisfactory data impact the overall measurement time.

Comparison of HMS techniques

| | FastHall™ | AC field | DC field |
|---|---|---|--|
| Eliminates field reversal | | AC field (sinusoidal) | X |
| Can be used with permanent magnets | FAST | X | MANUAL |
| Can be used with electromagnets | FAST | SLOWER WITH LOWER MOBILITIES | SLOWER WITH LARGE ELECTROMAGNETS |
| Can be used with superconducting magnets | FASTER THAN DC FIELD | X | SLOW |
| Measurement capability | Lower mobility: ~10 ⁻³ cm ² /V s and up | Lower mobility: ~10 ⁻³ cm ² /V s and up | Higher mobility: ~1 cm²/V s and up |

FastHall measurement requires Van der Pauw sample configurations (Hall bar configurations measured with DC field)

AC field measurement not currently supported in the M91—contact Lake Shore for more information

Materials

Solar cells

OPVs, a:Si, μ c-Si, CdTe, CuInGaSe (CIGS)

Organic electronics

OTFTs, Pentacene, Chalcogenides, OLEDs

Transparent conducting oxides

InSnO (ITO), ZnO, GaZnO, InGaZnO (IGZO)

III-V semiconductors

InP, InSb, InAs, GaN, GaP, GaSb, AIN based devices, high electron mobility transistors (HEMTs) and heterojunction bipolar transistors

II-VI semiconductors

CdS, CdSe, ZnS, ZnSe, ZnTe, HgCdTe

Elemental semiconductors

Ge, Si on insulator devices (SOI), SiC, doped diamond SiGe based devices: HBTs and FETs

Dilute magnetic semiconductors

GaMnAs, MnZnO

Half -Heusler compounds

TiNiSn, ZrNiSn, GdPtBi

Topological semi-metals

TaAs, WTe2, MoTe2

Topological insulators

Bi₂Te₃, Bi₂Se₃, Sb₂Te₃

Transition-metal Di-chalcogenides (TMDC)

WS₂, WSe₂, MoS₂, HfS₂

Other 2D materials

BN, graphene structures

Other conducting materials

Metal oxides
Organic and inorganic conductors

High temperature superconductors

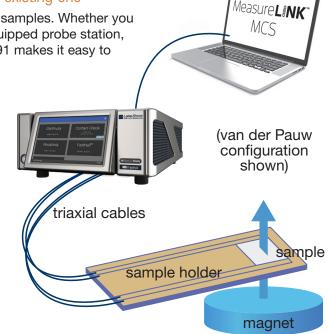
Key features

- Hall analysis including calculation of derived parameters for van der Pauw and Hall bar samples
- FastHall technology eliminates the need for magnetic field reversal when measuring van der Pauw samples—extends mobility range down to 0.001 cm²/V s
- Traditional DC field Hall measurement mode for both Hall bar and van der Pauw samples
- Automated operation for maximum convenience—includes automatic optimization of excitation values and measurement range
- Manual step-by-step mode for full parameter control
- High-resistance option—enables measurement of samples to 200 GΩ
- Outputs all measured values plus derived parameters
- 1-year calibration

A cost effective way to build a new Hall system or upgrade an existing one

A few simple connections and you're ready to begin analyzing your samples. Whether you choose to use a simple benchtop holder and magnet, a magnet-equipped probe station, an electromagnet platform, or a more specialized apparatus, the M91 makes it easy to bring state-of-the-art Hall measurement capability to your lab.

Lake Shore's versatile MeasureLINK-MCS software, included with each M91, gives you a simple way to customize, start, and stepthrough your measurement sequences, as well as chart, log and organize the results. MeasureLINK also enables automated control of field, management of sample temperature, and coordinated integration with other instrumentation and measurement protocols. With MeasureLINK, the M91 FastHall measurement controller becomes an even more powerful component to support your advanced semiconductor research.



The MeasureReady M91 FastHall measurement controller offers the ultimate in HMS speed, convenience, and precision

Measurement applications

The M91 is capable of running a wide array of Hall analysis functions including:

Hall voltage

- Resolution = 1 µV
- Noise = 0.1 μV (RMS), averaged over 1 power line cycle

Resistance/resistivity (four-contact in-line probe and van der Pauw)

- Calculated by instrument
- Resistance range 10 mΩ to 10 MΩ standard
- Up to 200 GΩ with high-resistance option

Magnetoresistance

 System provides field control to measure resistance as a function of magnetic field

Hall coefficient

- Calculated by instrument
- Derived from Hall voltage, magnetic field, and current

Hall mobility

- Calculated by instrument
- 10⁻³ to 10⁶ cm²/V s

Anomalous Hall effect (AHE)

 System provides field control to measure Hall voltage as a function of magnetic field

Carrier type/concentration/density

- Sheet or volume carrier concentration calculated
- Typical sheet carrier density ≤10¹⁷ cm⁻² (carrier density depends on measurement parameters)

More science, less time

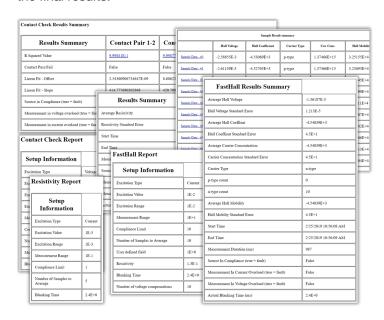
The M91 significantly reduces analysis time, in some cases by a factor of 100. Materials with resistances less than 1 M Ω can be analyzed in under a minute. Even extremely high resistances—up to 200 G Ω —can be measured quickly, although analysis time will increase. For resistances over 1 M Ω , the measurement time will depend on the time required for the voltages to stabilize.

Get all the data

Analysis of low mobility or high resistance materials faces challenges due to very low signal-to-noise ratios. Imprecise measurements are likely unless sophisticated techniques and/or larger measurement samples are used.

With some HMS solutions, the researcher often has little chance to double check the intermediate results of the analysis, and can therefore be easily misled as to the validity of the reported results.

The M91 collects all the data. In addition to performing the complete Hall analysis and outputting the usual measured and derived mobility values, the M91 can also generate detailed reports including all of the supporting intermediate data, so the researcher can readily confirm the integrity of the final results.



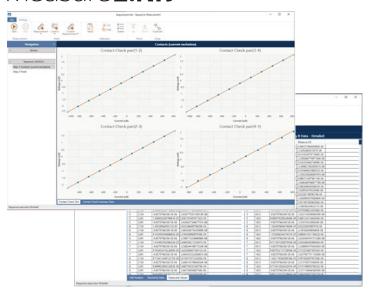
Built for science, designed for people

The M91 is a powerful research instrument that incorporates Lake Shore's decades of experience in Hall effect measurement. It's also really easy to work with.

Easy to get started

- Begin using the M91 right out of the box with the included MeasureLINK-MCS application software
- Install MeasureLINK on your laptop and easily enter measurement parameters
- MeasureLINK enables you to easily initiate Hall measurement sequences and view graphical results
- Measurement sequences can be readily customized and adapted to your research needs

Measure**L**₽NK™

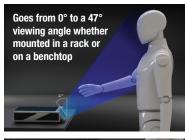


Easy to use

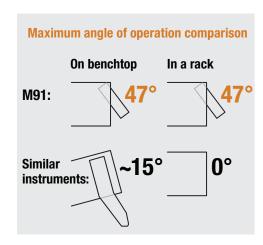
- Onboard touchscreen UI displays measurement process steps as they execute in real time, and provides quick access to view high-level measurement results
- Ergonomically designed package features TiltView[™] display for best visibility, whether on a bench or mounted in a rack

See and operate more easily with TiltView™





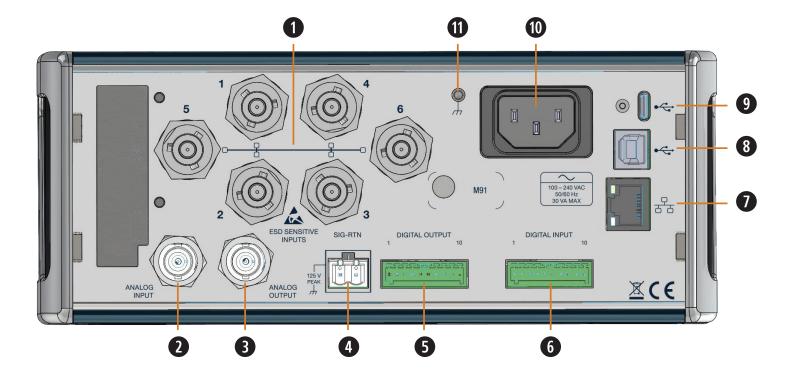




Easy to integrate

- Simple SCPI command interface
- MeasureLINK software facilitates integration with third party instruments and software
- Hardware digital and analog I/O for OEM system interfaces

MeasureReady[™] M91 rear panel



- Triaxial sample connectors
- 2 Analog input
- 3 Analog output
- 4 Signal RTN

- **5** Digital output
- 6 Digital input
- **7** RJ-45 Ethernet interface
- USB communications interface
- USB thumb drive interface
- 10 Line input assembly
- 1 Chassis ground connection

Be future-ready with MM Measure Ready

With free online firmware updates, your instrument can always have the most current capabilities. And as Lake Shore introduces new options in the future, you can purchase and download them to your instrument. This allows the controller to grow as your measurement needs evolve.

M91 specifications

Hall measurement

FastHall[™] method (no physical field reversal) — van der Pauw samples Traditional DC method — Hall bar and van der Pauw samples

Derived narameters

Hall coefficient, Hall mobility, resistivity, carrier concentration

Sheet resistance

Lowest range: 10 mΩ Highest range: up to 10 $M\Omega$

Highest range with M9-ADD-HR high resistance option: up to 200 GΩ

Hall mobility range

0.001 to 106 cm²/V s

Programmable limits

I out: compliance voltage; V out: current limit

±5% of setting (when setting is >10% of its full-scale range) Positive output: **Negative output:** ±5% of setting (when setting is >10% of its full-scale range)

Programming resolution current limit: 0.1% of full-scale current range (auto

selected)

Programming resolution voltage limit: 10 mV

Analog input

Analog input raw signal accuracy: ±300 mV of reading

Raw analog input voltage range: ±11 V Safe input voltage range: ±15 V Compliance voltage (typical): ≤10 V Current limit (typical): < 0.1 A

Analog output

Analog output raw signal accuracy: ±300 mV of setting

Raw analog output voltage range: ±11 V rails, ±15 V max during overload

Digital input

Number of independent inputs: Input isolation: Optical Maximum low-level input voltage: 1 V Minimum high-level input voltage: 4 V -5 V to 32 V Safe input voltage range:

Digital output

Number of independent outputs:

Solid state Relay type:

Digital output relay max current: 1.5 A Digital output relay max voltage: 32 V

Rear panel test connectors

Sample connections: 6 individual 3-lug socket triaxial connectors

Analog input BNC Analog output BNC

10-pin Phoenix connector for digital output 10-pin Phoenix connector for digital input 2-pin Phoenix connector for signal return

Front panel

Display: 5 in capacitive touch, color TFT-LCD WVGA

 (800×480) with LED backlight

Interface

USB host

Type USB 3.0, mass storage class (MSC) device **Function** Firmware updates, flash drive support

Location Rear panel USB Type-C™ Connector

USB device

Baud rate

Connector

USB 2.0 Type

Function Emulates a standard RS-232 serial port Standard commands for programmable Protocol

> instruments (SCPI) 921,600 USB Type-B

LabVIEW™ and IVI.NET drivers Software support

(see www.lakeshore.com)

Ethernet

Function TCP/IP command and control, mobile app

Standard commands for programmable Application layer protocol

instruments (SCPI)

RJ-45 Connector Speed 1 Gb/s

LabVIEW™ and IVI.NET drivers Software support

(see www.lakeshore.com)

General

Power requirement:

Operating conditions: 23°C ±5°C at rated accuracy; 10°C to 35°C at reduced accuracy,

<70% RH non-condensing

Instrument maximum field exposure: Operational limit <10 mT DC, 1 mT RMS;

. Guaranteed performance <2 mT RMS

100 V to 240 V (universal input),

50 to 60 Hz. 30 VA

Size: 216 mm W \times 87 mm H \times 369 mm D

 $(8.5 \text{ in} \times 3.4 \text{ in} \times 14.5 \text{ in})$, half rack

Weight: 3.2 kg Approval: CE mark Warm-up time: 30 min Power consumption: 35 W maximum

Measurement performance

| | | | Voltage measurement range | | | | |
|--------------------------|----------|---|---------------------------|--------|--------|--------|--------|
| | | | 1 mV | 10 mV | 100 mV | 1 V | 10 V |
| | 1 μΑ | Resistance at maximum voltage | 1 kΩ | 10 kΩ | 100 kΩ | 1 ΜΩ | 10 ΜΩ |
| | | Accuracy (1 year) calibration temperature °C \pm 5 °C \pm % reading ¹ | 0.2% | 0.06% | 0.06% | ** | ** |
| | | Temperature coefficient/°C 10 °C to 35 °C \leq 65% RH non-condensing \pm % reading (typical) | 0.001% | 0.001% | 0.001% | ** | ** |
| | 10 μΑ | Resistance at maximum voltage | 100 Ω | 1 kΩ | 10 kΩ | 100 kΩ | 1 ΜΩ |
| | | Accuracy (1 year) calibration temperature ${}^{\circ}C \pm 5 {}^{\circ}C \pm \%$ reading ¹ | 0.2% | 0.06% | 0.06% | 0.06% | ** |
| | | Temperature coefficient/°C 10 °C to 35 °C \leq 65% RH non-condensing \pm % reading (typical) | 0.001% | 0.001% | 0.001% | 0.001% | ** |
| as | 100 μΑ | Resistance at maximum voltage | 10 Ω | 100 Ω | 1 kΩ | 10 kΩ | 100 kΩ |
| ang | | Accuracy (1 year) calibration temperature °C \pm 5 °C \pm % reading ¹ | 0.2% | 0.2% | 0.06% | 0.06% | 0.06% |
| Current excitation range | | Temperature coefficient/°C 10 °C to 35 °C \leq 65% RH non-condensing \pm % reading (typical) | 0.001% | 0.001% | 0.001% | 0.001% | 0.5% |
| exci | 1 mA | Resistance at maximum voltage | 1 Ω | 10 Ω | 100 Ω | 1 kΩ | 10 kΩ |
| rent | | Accuracy (1 year) calibration temperature °C \pm 5 °C \pm % reading ¹ | 0.2% | 0.2% | 0.2% | 0.06% | 0.06% |
| Cur | | Temperature coefficient/°C 10 °C to 35 °C \leq 65% RH non-condensing \pm % reading (typical) | 0.001% | 0.001% | 0.001% | 0.001% | 0.5% |
| | | Resistance at maximum voltage | 0.1 Ω | 1 Ω | 10 Ω | 100 Ω | 1 kΩ |
| | 10 mA | Accuracy (1 year) calibration temperature °C \pm 5 °C \pm % reading ¹ | 0.5% | 0.2% | 0.2% | 0.2% | 0.2% |
| | | Temperature coefficient/°C 10 °C to 35 °C \leq 65% RH non-condensing \pm % reading (typical) | 0.001% | 0.001% | 0.001% | 0.001% | 0.5% |
| | 100 mA | Resistance at maximum voltage | 0.01 Ω | 0.1 Ω | 1 Ω | 10 Ω | 100 Ω |
| | | Accuracy (1 year) calibration temperature °C \pm 5 °C \pm % reading ^{1,2} | 2.0% | 0.2% | 0.2% | 0.2% | ** |
| | 100 IIIA | Temperature coefficient/°C 10 °C to 35 °C \leq 65% RH non-condensing \pm % reading (typical) | 0.001% | 0.001% | 0.001% | 0.001% | ** |

^{**}Range available, not specified

All accuracies based on current reversal measurements

With high resistance option only

| | | | Current measi | rement range | |
|-------------|--|--------|---------------|--------------|--------|
| | | 10 nA | 100 μΑ | 10 mA | 100 mA |
| | Resistance at maximum current | 1 ΜΩ | 1 kΩ | 1 Ω | 0.1 Ω |
| 10 mV | Accuracy (1 year) calibration temperature °C ± 5 °C ± % reading¹ | 0.5% | ** | ** | ** |
| | Temperature coefficient/°C 10 °C to 35 °C \leq 65% RH non-condensing \pm % reading (typical) | 0.001% | ** | ** | ** |
| nge | Resistance at maximum current | 10 ΜΩ | 10 kΩ | 10 Ω | 1 Ω |
| 100 mV | Accuracy (1 year) calibration temperature °C ± 5 °C ± % reading¹ | 0.5% | ** | ** | ** |
| excitation | Temperature coefficient/°C 10 °C to 35 °C \leq 65% RH non-condensing \pm % reading (typical) | 0.001% | ** | ** | ** |
| | Resistance at maximum current | 100 ΜΩ | 100 kΩ | 100 Ω | 10 Ω |
| Voltage 1 A | Accuracy (1 year) calibration temperature °C ± 5 °C ± % reading ¹ | 0.8% | 0.5% | ** | ** |
| Volt | Temperature coefficient/°C 10 °C to 35 °C \leq 65% RH non-condensing \pm % reading (typical) | 0.001% | 0.001% | ** | ** |
| | Resistance at maximum current | 1 GΩ | 1 ΜΩ | 1 kΩ | 100 Ω |
| 10 V | Accuracy (1 year) calibration temperature °C ± 5 °C ± % reading¹ | 0.5% | 0.5% | ** | ** |
| | Temperature coefficient/°C 10 °C to 35 °C \leq 65% RH non-condensing \pm % reading (typical) | 0.001% | 0.001% | ** | ** |

^{**} Range available, not specified

Calibration temperature is the ambient temperature during factor calibration; typically, 23 °C; reported by the instrument

Guaranteed when lead resistance is 0.1 Ω or less

¹ Calibration temperature is the ambient temperature during factor calibration; typically, 23 °C; reported by the instrument All accuracies based on voltage reversal measurements.

| Current measurement range | DC Accuracy (1 year) calibration temperature °C ± 5 °C ± % reading¹ | | |
|---------------------------|---|--|--|
| 10 mA | 0.3% | | |
| 100 mA | 0.3% | | |

¹ Calibration temperature is the ambient temperature during factor calibration; typically, 23 °C; reported by the instrument

Voltage and current excitation specifications

| Voltage excitation range | Programming resolution (0.001%) | Temperature coefficient/°C 10 °C to 35 °C ± (% setting + offset), typical |
|--------------------------|------------------------------------|--|
| 10 mV | 100 nV | $0.06\% + 4 \mu V$ |
| 100 mV | 1 μV | $0.005\% + 4~\mu\text{V}$ |
| 1 V | 10 μV | $0.0004\% + 20 \mu\text{V}$ |
| 10 V | 100 μV | 0.0004% + 200 μV |
| Current excitation range | Programming resolution (0.001%) | Temperature coefficient/°C 10 °C to 35 °C ± (% setting + offset), typical |
| 1 μΑ | 10 pA | 0.002% + 9 pA |
| 10 μΑ | 100 pA | 0.0004% + 20 pA |
| 100 μΑ | 1 nA | 0.0004% + 90 pA |
| 1 mA | 10 nA | 0.0004% + 40 pA |
| 10 mA | 100 nA | 0.0004% + 4 nA |
| 100 mA | 1 μΑ | 0.0004% + 40 nA |

Voltage and current measurement specifications

| Voltage measurement range | Temperature coefficient/°C 10 °C to 35 °C ± offset (typical) |
|---------------------------|---|
| 1 mV | 50 nV |
| 10 mV | 50 nV |
| 100 mV | 200 nV |
| 1 V | 2 μV |
| 10 V | 20 μV |
| Current measurement range | Temperature coefficient/°C 10 °C to 35 °C ± offset (typical) |
| 10 nA | 2 pA |
| 10 μΑ | 7 pA |
| 10 mA | 7 nA |
| 100 mA | 70 nA |

Ordering information M91 Mea

M91 MeasureReady® M91 FastHall™

controller with accessory kit

(M91-ACC-KIT)

M91-HR MeasureReady M91 FastHall controller

with high resistance option and accessory kit (M91-ACC-KIT)

M9-ADD-HR M91 firmware upgrade to include high

resistance samples to 200 $G\Omega$

MR-GPIB-USB GPIB to USB adapter for XIP instruments

RM-1/2 Kit for mounting a single half-rack

instruments in a 483 mm (19 in) rack

RM-2 Kit for mounting two adjacent half-rack

instruments in a 483 mm (19 in) rack

843-076 Low noise triaxial cable, 3-slot,

1 m (3 ft)

843-062 Low noise triaxial cable, 3-slot,

3.7 m (12 ft)

P12379 BNC female to triaxial adapter, TRB male,

3 lug, isolated, 50 Ω

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